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FAIRCHILD SEMICONDUCTOR™

August 2000

QFET™

FQS4900

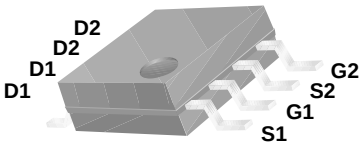
Dual N & P-Channel, Logic Level MOSFET

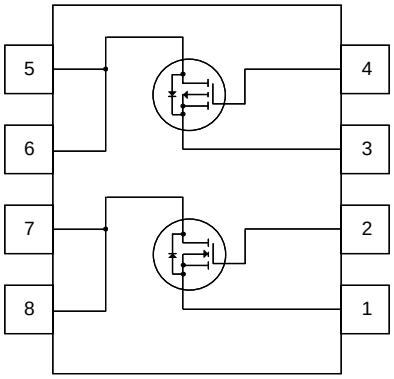
General Description

These dual N and P-channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. This device is well suited for high interface in telephone sets.

Features

- N-Channel 1.3A, 60V, $R_{DS(on)}$ = 0.55 Ω @ V_{GS} = 10 V
  $R_{DS(on)}$ = 0.65 Ω @ V_{GS} = 5 V
  P-Channel -0.3A, -300V, $R_{DS(on)}$ = 15.5 Ω @ V_{GS} = -10 V
  $R_{DS(on)}$ = 16 Ω @ V_{GS} =- 5 V
- Low gate charge (typical N-Channel 1.6 nC)
  (typical P-Channel 3.6 nC)
- Fast switching
- Improved dv/dt capability





Absolute Maximum Ratings

T_A = 25°C unless otherwise noted

Symbol	Parameter		N-Channel	P-Channel	Units
V_{DSS}	Drain-Source Voltage		60	-300	V
I_D	Drain Current - Continuous (T_A = 25°C)		1.3	-0.3	A
	- Continuous (T_A = 70°C)		0.82	-0.19	A
I_{DM}	Drain Curent - Pulsed	(Note 1)	5.2	-1.2	A
V_{GSS}	Gate-Source Voltage		± 20		V
dv/dt	Peak Diode Recovery dv/dt	(Note 2)	7.0	4.5	V/ns
P_D	Power Dissipation (T_A = 25°C)		2.0		W
	(T_A = 70°C)		1.3		W
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150		°C

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	°C/W

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Electrical Characteristics

T_A = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 µA	N-Ch	60	--	--	V
		V_{GS} = 0 V, I_D = -250 µA	P-Ch	-300	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 60 V, V_{GS} = 0 V	N-Ch	--	--	1	µA
		V_{DS} = 48 V, T_C = 55°C		--	--	10	µA
		V_{DS} = -300 V, V_{GS} = 0 V	P-Ch	--	--	-1	µA
		V_{DS} = -240 V, T_C = 55°C		--	--	-10	µA
I_{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 20 V, V_{DS} = 0 V	All	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -20 V, V_{DS} = 0 V	All	--	--	-100	nA
On Characteristics							
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = 4V, I_D = 20 mA	N-Ch	1.0	--	1.95	V
		V_{DS} = 4V, I_D = -20 mA	P-Ch	-1.0	--	-1.95	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 0.65 A	N-Ch	--	0.39	0.55	Ω
		V_{GS} = 5 V, I_D = 0.65 A		--	0.46	0.65	Ω
		V_{GS} = -10 V, I_D = -0.15 A	P-CH	--	11.2	15.5	Ω
		V_{GS} = -5 V, I_D = -0.15 A		--	11.4	16	Ω
g_{FS}	Forward Transconductance	V_{DS} = 10 V, I_D = 0.65 A	N-CH	--	1.7	--	S
		V_{DS} = -10 V, I_D = -0.15 A	P-CH	--	0.6	--	S
Switching Characteristics							
$t_{d(on)}$	Turn-On Delay Time	N-Channel V_{DD} = 30 V, I_D = 1.3 A, R_G = 25 Ω	N-Ch	--	5.7	21	ns
			P-Ch	--	10	30	ns
t_r	Turn-On Rise Time		N-Ch	--	21	50	ns
			P-Ch	--	25	60	ns
$t_{d(off)}$	Turn-Off Delay Time	P-Channel V_{DD} = -150 V, I_D = -0.3 A, R_G = 25 Ω	N-Ch	--	11	32	ns
			P-Ch	--	35	80	ns
t_f	Turn-Off Fall Time		N-Ch	--	17	45	ns
			P-Ch	--	47	105	ns
Q_g	Total Gate Charge	N-Channel V_{DS} = 48 V, I_D = 1.3 A, V_{GS} = 5 V P-Channel V_{DS} = -240 V, I_D = -0.3 A, V_{GS} = -5 V	N-Ch	--	1.6	2.1	nC
			P-Ch	--	3.6	4.7	nC
Q_{gs}	Gate-Source Charge		N-Ch	--	0.28	--	nC
			P-Ch	--	0.42	--	nC
Q_{gd}	Gate-Drain Charge		N-Ch	--	0.82	--	nC
			P-Ch	--	2.1	--	nC
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current		N-Ch	--	--	1.3	A
			P-Ch	--	--	-0.3	A
V_{SD}	Drain-Source Diode Forward Voltage	V_{GS} = 0 V, I_S = 1.3 A	N-Ch	--	--	1.5	V
		V_{GS} = 0 V, I_S = -0.3 A	P-Ch	--	--	-4.0	V

Notes:
1. Repetitive Rating : Pulse width limited by maximum junction temperature
3. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%
4. Essentially independent of operating temperature

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Typical Characteristics : N-Channel

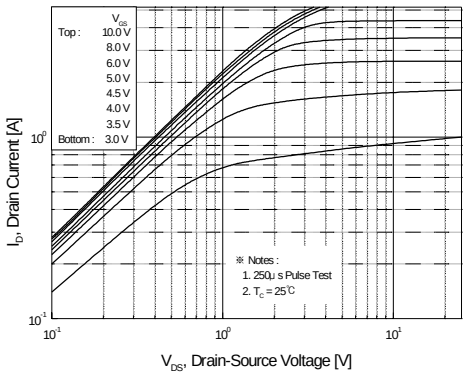

Figure 1. On-Region Characteristics

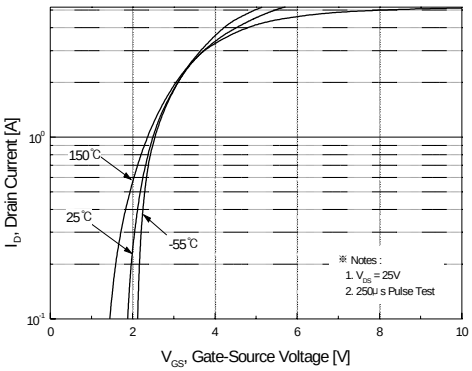

Figure 2. Transfer Characteristics

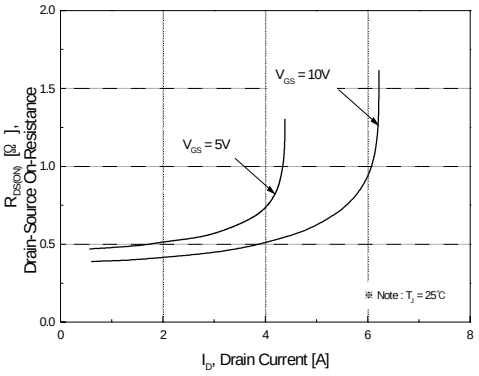

Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

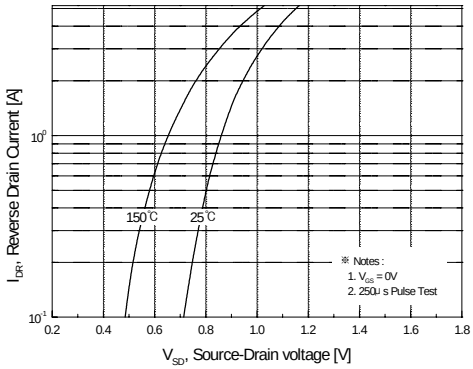

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

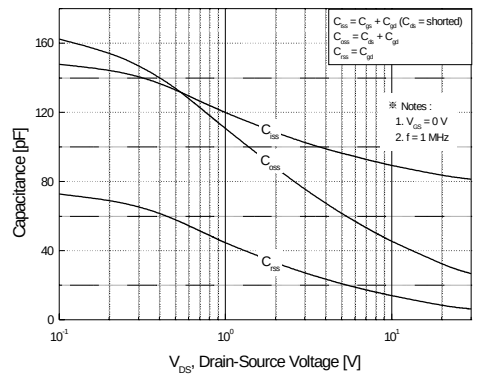

Figure 5. Capacitance Characteristics

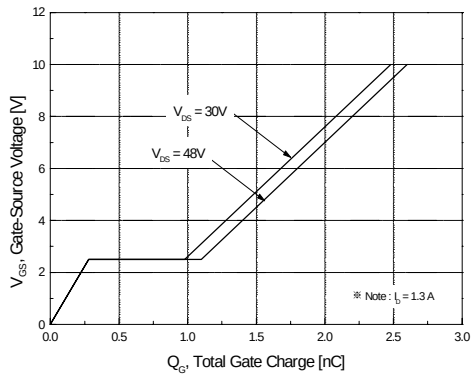

Figure 6. Gate Charge Characteristics

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Typical Characteristics : N-Channel (Continued)

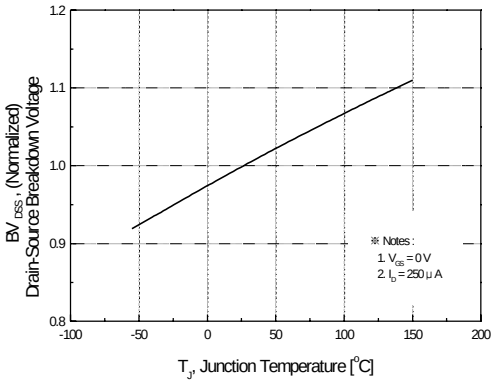

Figure 7. Breakdown Voltage Variation vs. Temperature

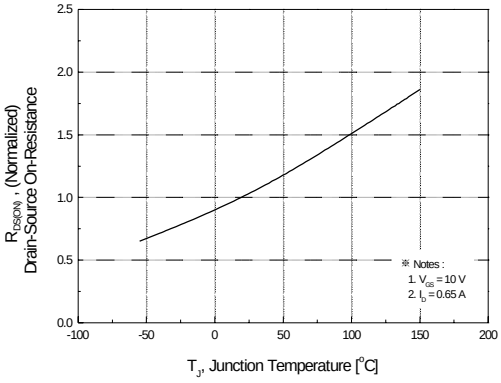

Figure 8. On-Resistance Variation vs. Temperature

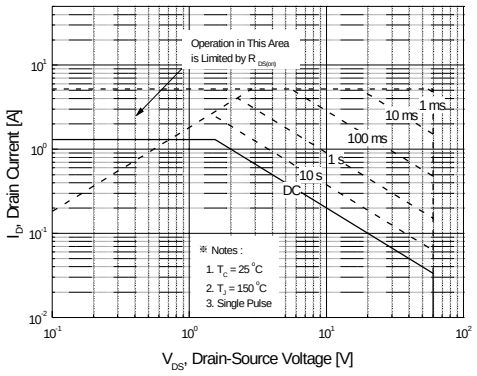

Figure 9. Maximum Safe Operating Area

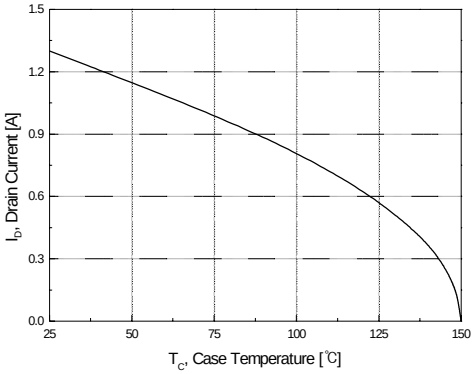

Figure 10. Maximum Drain Current vs. Case Temperature

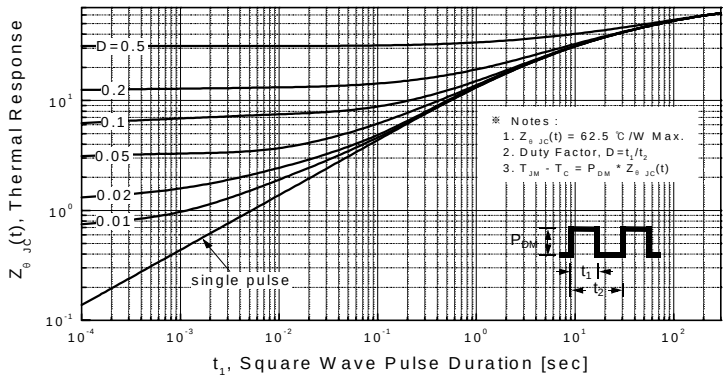

Figure 11. Transient Thermal Response Curve

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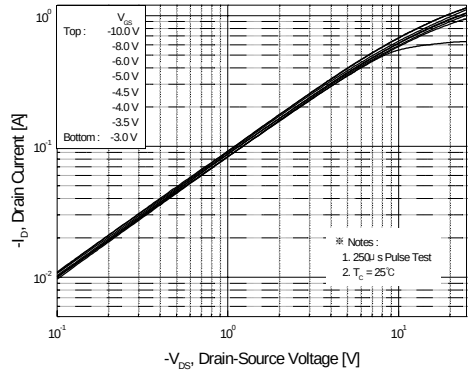
Typical Characteristics : P-Channel (Continued)



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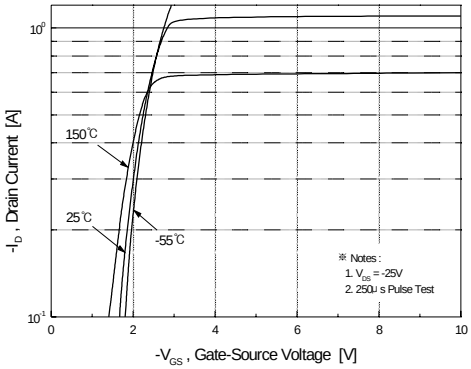

Figure 2. Transfer Characteristics

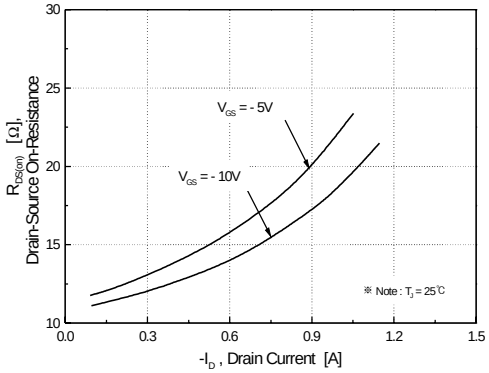

Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

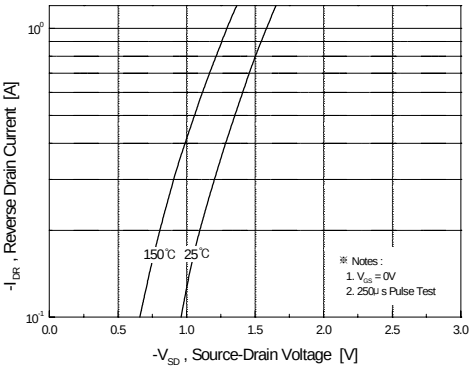

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

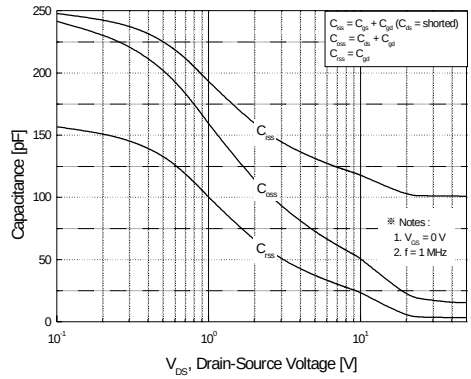

Figure 5. Capacitance Characteristics

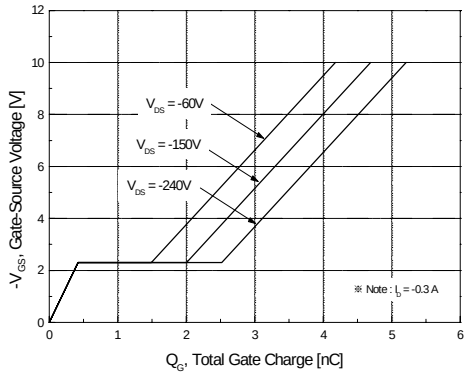

Figure 6. Gate Charge Characteristics

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Typical Characteristics : P-Channel (Continued)

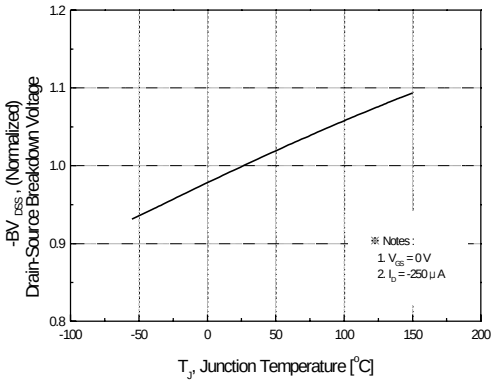

Figure 7. Breakdown Voltage Variation vs. Temperature

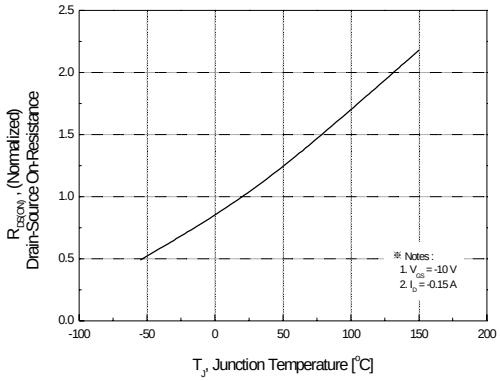

Figure 8. On-Resistance Variation vs. Temperature

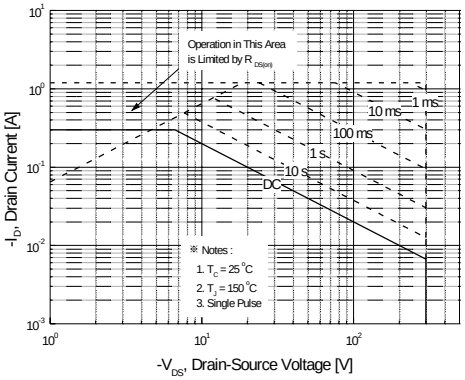

Figure 9. Maximum Safe Operating Area

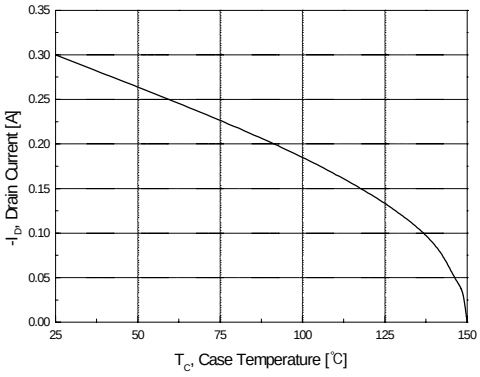

Figure 10. Maximum Drain Current vs. Case Temperature

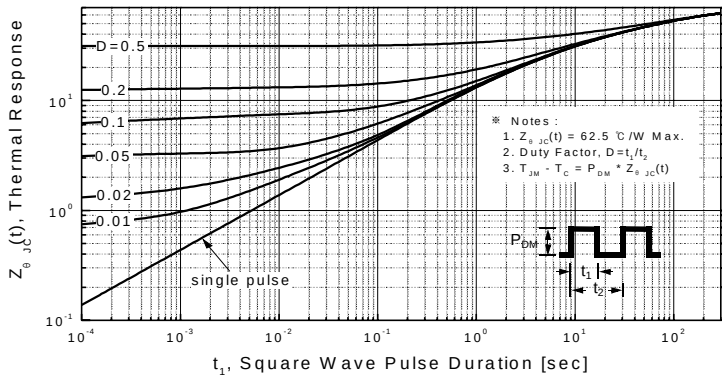

Figure 11. Transient Thermal Response Curve

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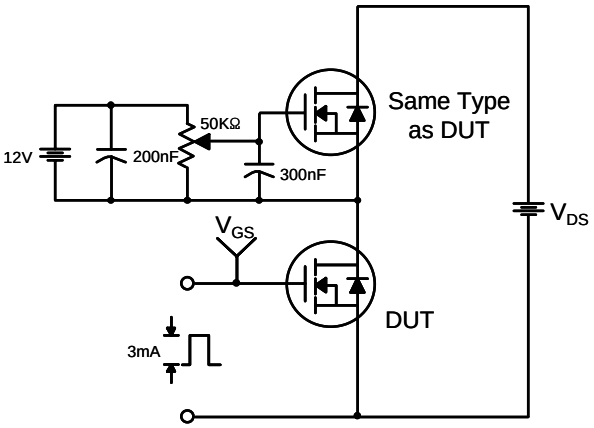
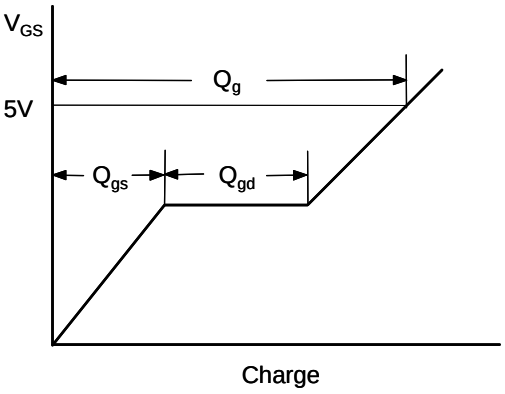
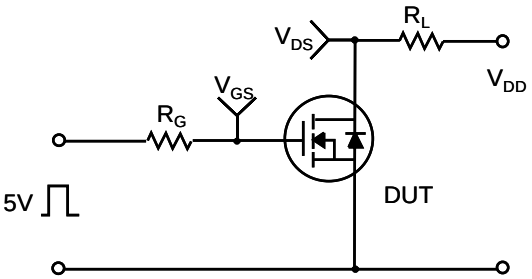
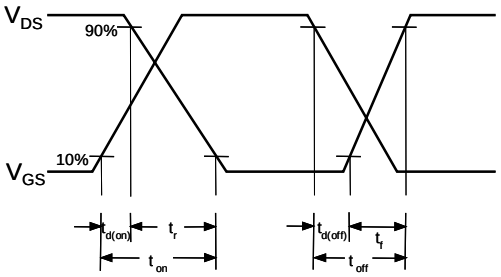
Gate Charge Test Circuit & Waveform





Resistive Switching Test Circuit & Waveforms





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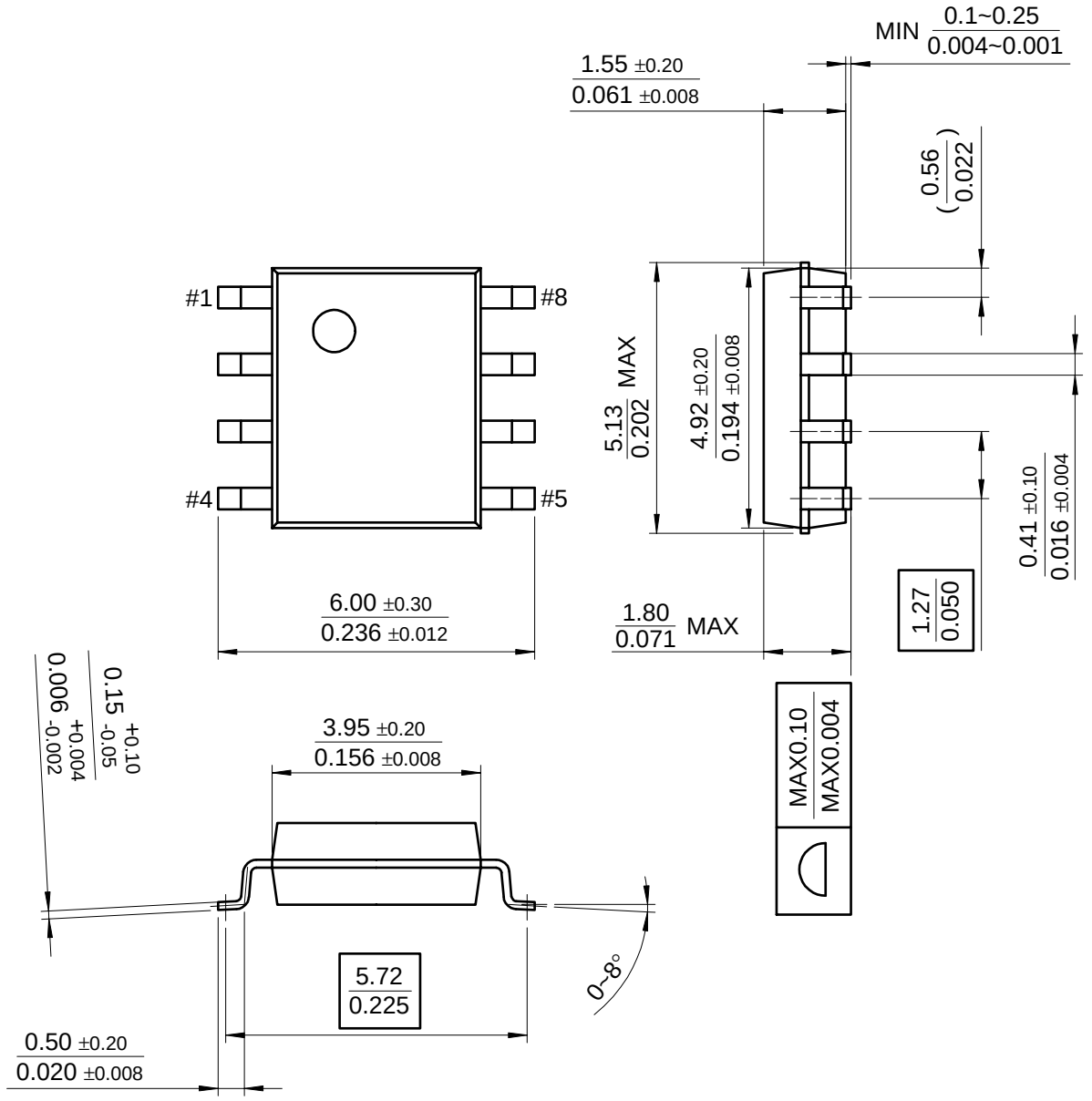
Package Dimensions

8-SOP



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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
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Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

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